Uncertainty	Affects shape	Corr. years	Relative effect on expected yield
Experimental			
Integrated luminosity	—	Partial	1.6%
Pileup modeling	✓	✓	0.2–3.1%
L1 trigger	✓	✓	0.3–1.1%
Electron ID	✓	✓	0.7–2.8%
Electron ID ($p_T^e > 200\,\text{GeV}$)	✓	—	0.1–1.2%
Electron trigger	—	—	0.5%
Muon ID (stat)	✓	—	0.1–0.6%
Muon ID (syst)	✓	✓	0.2–0.7%
Muon trigger	✓	—	0.1–0.7%
Photon ID	✓	✓	0.6–6.0%
Photon ID ($p_T^\gamma > 200\,\text{GeV}$)	✓	—	2.1–4.7%
Photon ID (high p_T extrapolation)	✓	—	Typically 3.0–9.0%, max. 14%
Photon (e veto)	—	—	1%
Photon energy scale	✓	✓	Typically 0.1–4.8%, max. 13%
Jet energy scale	✓	—	1–4%
p_T^{miss} scale	✓	Partial	0.1–10.1%
e $\rightarrow \gamma$ misidentification	✓	—	Typically 6.7–18%, max. 25%
Jet $\rightarrow \gamma$ misidentification	✓	—	10–45%
Misidentified e	✓	—	Typically 13–36%, max. 75%
Misidentified μ	✓	—	Typically 16–42%, max. 70%
Theoretical			
γ acceptance (scale)	✓	✓	0.3–1.7%
γ acceptance (PDF)	✓	✓	Typically 0.5–2.2%, max. 7.6%
γ out-of-acceptance (scale)	✓	✓	5.2–12%
γ parton shower modeling	✓	✓	0.2–1.3%
Background normalization (scale)	—	✓	2.0–16%
Background normalization (PDF)	—	✓	4.2–4.8%